

THIS DRAWING INACTIVE FOR NEW DESIGN AS OF 10 FEB 1988 USE M38510/35202--.		REVISIONS											
		LTR	DESCRIPTION	DATE	APPROVED								
		A	Delete short circuit output current (I_{OS}) from table I. Change in I_{CCH} test condition V_{IN} , in table I. Editorial changes throughout. Device 01 inactivated for new design.	3 MAR 1988									

REV																					
PAGE																					
REV STATUS	REV	A	A	A	A	A	A	A	A	A	A										
OF PAGES	PAGES	1	2	3	4	5	6	7	8	9	10										

Defense Electronics Supply Center Dayton, Ohio Original date of drawing: 20 July 1987 AMSC N/A	PREPARED BY 	MILITARY DRAWING This drawing is available for use by all Departments and Agencies of the Department of Defense TITLE: MICROCIRCUIT, DIGITAL, ADVANCED SCHOTTKY TTL, NAND BUFFER, MONOLITHIC SILICON DWG NO. 5962-86872
	CHECKED BY 	
	APPROVED BY 	
	SIZE A CODE IDENT. NO. 67268	
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

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MAY 86

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-86872	01	C	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54F38	Quad two-input NAND buffer with open collector outputs

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
C	D-1 (14-lead, .785" x .310" x .200"), dual-in-line package
D	F-2 (14-lead, .390" x .260" x .085"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range - - - - -	-0.5 V dc minimum to +7.0 V dc maximum
Input voltage range- - - - -	-1.2 V dc minimum at -18 mA to +7.0 V dc maximum
Output sink current- - - - -	128 mA
Maximum power dissipation (P_D) - - - - -	165 mW
Thermal resistance, junction-to-case (θ_{JC}):- - - - -	See MIL-M-38510, appendix C
Lead temperature (soldering, 10 seconds) - - - - -	+300°C
Junction temperature (T_J)- - - - -	+175°C
Storage temperature range- - - - -	-65°C to +150°C

1.4 Recommended operating conditions.

Supply voltage (V_{CC}) - - - - -	4.5 V dc minimum to 5.5 V dc maximum
Minimum high level input voltage (V_{IH}) - - - - -	2.0 V dc
Maximum low level input voltage (V_{IL})- - - - -	0.8 V dc
Case operating temperature range (T_C)- - - - -	-55°C to +125°C

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by contractors in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Switching waveforms and test circuit. The switching waveforms and test circuit shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Maximum collector cut-off current	I _{CEX}	V _{CC} = 4.5 V, V _{IN} = 0.8 V Inputs not under test = 5.5 V Outputs under test are at 4.5 V (V _{OH})	1, 2, 3		250	μA
Low level output voltage	V _{OL}	V _{CC} = 4.5 V, I _{OL} = 20 mA, V _{IN} = 2.0 V	1, 2, 3		0.5	V
Input clamp voltage	V _{IC}	V _{CC} = 4.5 V, I _{IN} = -18 mA	1		-1.2	V
High level input current	I _{IH1}	V _{CC} = 5.5 V, V _{IN} = 2.7 V	1, 2, 3		20	μA
	I _{IH2}	V _{CC} = 5.5 V, V _{IN} = 7.0 V	1, 2, 3		100	μA
Low level input current	I _{IL}	V _{CC} = 5.5 V, V _{IN} = 0.5 V	1, 2, 3		-1.2	mA
Supply current	I _{CCH}	V _{CC} = 5.5 V, V _{IN} = GND	1, 2, 3		7	mA
	I _{CCL}	V _{CC} = 5.5 V, V _{IN} = 5.5 V	1, 2, 3		30	mA
Functional tests		See 4.3.1c	7			
Propagation delay time, A, B to Y	t _{PHL}	V _{CC} = 5.0 V, R _L = 500Ω ±2% C _L = 50 pF ±10% See figure 3	9, 10, 11	1.0	6	ns
	t _{PLH}		9, 10, 11	7.0	15	ns

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3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, D, or E using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 7 tests shall verify truth table.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883:

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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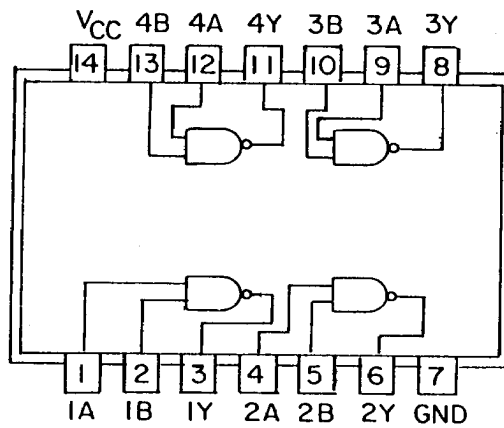
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Cases C and D



Case 2
(top view)

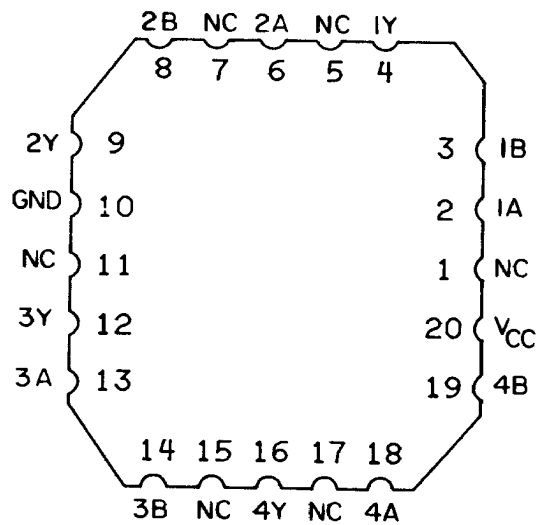


FIGURE 1. Terminal connections and logic diagram.

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Truth table (each gate)		
Input		Output
A	B	Y
L	L	H
H	L	H
L	H	H
H	H	L

Positive logic $Y = \overline{AB}$

L = Low voltage level

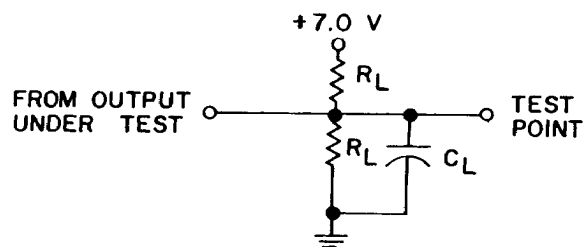
H = High voltage level

FIGURE 2. Truth table.

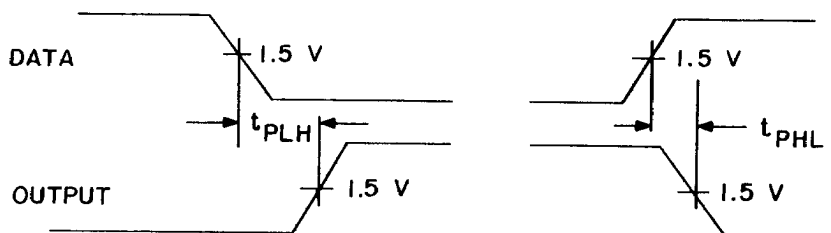
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TEST CIRCUIT



- NOTES: 1. The pulse generator shall have the following characteristics:
 $t_r = t_f \leq 2.5 \text{ ns}$; $\text{PRR} \leq 1 \text{ MHz}$; $Z_{\text{OUT}} = 50\Omega$.
2. Inputs not under test are at GND or 2.7 V.
3. $C_L = 50 \text{ pF} \pm 10\%$, including scope probe, wiring, and stray capacitance without the package in the test fixture.
4. $R_L = 500\Omega \pm 2\%$.
5. Voltage measurements shall be made with respect to the network ground terminal.

FIGURE 3. Switching waveforms and test circuit.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability.

- a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/35202--.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>	Replacement military specification part number
5962-8687201CX <u>2/</u>	18324	54F38/BCA	M38510/35202BCX
5962-8687201DX <u>2/</u>	18324	54F38/BDA	M38510/35202BDX
5962-86872012X <u>2/</u>	18324	54F38/B2C	M38510/35202B2X

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

2/ Inactive for new design. Use QPL-38510 product.

Vendor CAGE number

18324

Vendor name and address

Signetics Corporation
4130 South Market Court
Sacramento, CA 95834

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